

FCC ID: 2ASV5-V50X

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHZ})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

WIFI:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
802.11b	2.412	2.5	1.78	3±1	4	2.51	<5	0.78022	3.00	YES
	2.442	3.38	2.18	3±1	4	2.51	<5	0.78506	3.00	YES
	2.462	2.51	1.78	3±1	4	2.51	<5	0.78827	3.00	YES
802.11g	2.412	1.93	1.56	2.5±1	3.5	2.24	<5	0.69537	3.00	YES
	2.442	2.94	1.97	2.5±1	3.5	2.24	<5	0.69969	3.00	YES
	2.462	3.34	2.16	2.5±1	3.5	2.24	<5	0.70254	3.00	YES
802.11n HT20	2.412	1.82	1.52	2.5±1	3.5	2.24	<5	0.69537	3.00	YES
	2.442	2.81	1.91	2.5±1	3.5	2.24	<5	0.69969	3.00	YES
	2.462	3.13	2.06	2.5±1	3.5	2.24	<5	0.70254	3.00	YES
802.11n HT40	2.412	2.34	1.71	2±1	3	2.00	<5	0.61975	3.00	YES
	2.442	2.61	1.82	2±1	3	2.00	<5	0.62360	3.00	YES
	2.452	2.9	1.95	2±1	3	2.00	<5	0.62487	3.00	YES

Conclusion:

For the max result : 0.78827/Kg ≤ 3.0 for 1g SAR, No SAR is required.

Signature:

Date: 2019-08-28

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